



CMOS High Voltage Logic – CD4071B

CMOS Quad 2-Input OR Gate in bare die form

Rev 1.0
19/09/18

Description

The CD4071B provides the system designer with direct implementation of the positive-logic OR function. The device has equal source and sink current capabilities and conforms to standard B series output drive. Device outputs are buffered which improves transfer characteristics by providing very high gain. The device is capable of driving x2 low power TTL loads or x1 LSTTL load. The CD4071B is primarily used for higher voltage acceptance and where low power dissipation and/or high noise immunity are required.

Features:

- High Input Voltage up to 20V
- Symmetrical Output Characteristics
- Max input current 1µA at 18V over full Military Temperature Range
- Low Power TTL compatible
- Specified at 5V, 10V & 15V
- Direct drop-in replacement for obsolete components in long term programs.

Ordering Information

The following part suffixes apply:

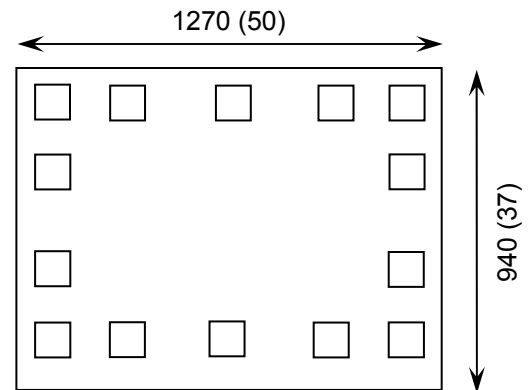
- No suffix - MIL-STD-883 /2010B Visual Inspection
- "H" - MIL-STD-883 /2010B Visual Inspection + MIL-PRF-38534 Class H LAT
- "K" - MIL-STD-883 /2010A Visual Inspection (Space) + MIL-PRF-38534 Class K LAT

LAT = Lot Acceptance Test.

For further information on LAT process flows see below.

www.siliconsupplies.com/quality/bare-die-lot-qualification

Die Dimensions in µm (mils)



Supply Formats:

- Default – Die in Waffle Pack (400 per tray capacity)
- Sawn Wafer on Tape – On request
- Unsawn Wafer – On request
- Die Thickness <=> 635µm(25 Mils) – On request
- Assembled into Ceramic Package – On request

Mechanical Specification

| | | |
|------------------------|--------------------------|------------|
| Die Size (Unsawn) | 1270 x 940 50 x 37 | µm mils |
| Minimum Bond Pad Size | 106 x 106 4.17 x 4.17 | µm mils |
| Die Thickness | 635 (±20) 25 (±0.79) | µm mils |
| Top Metal Composition | Al 1%Si 1.1µm | |
| Back Metal Composition | N/A – Bare Si | |

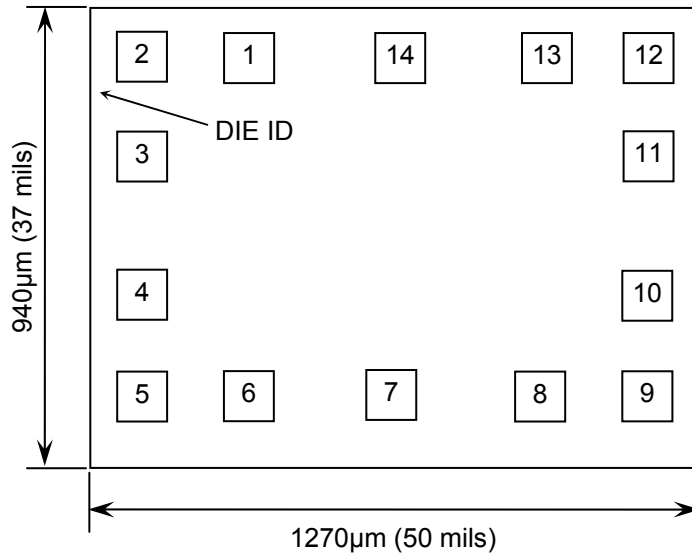




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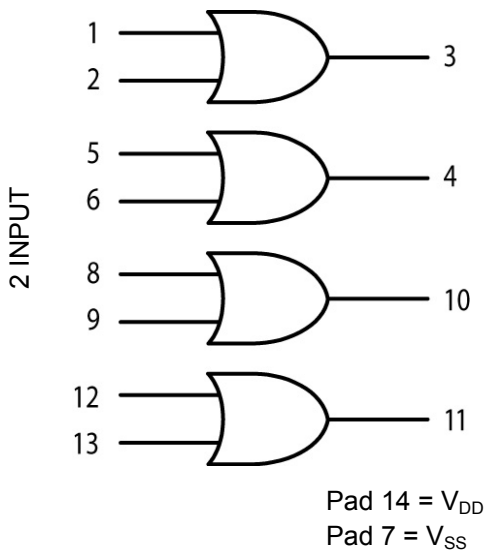
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Pad Layout and Functions



| PAD | FUNCTION |
|---|-----------------|
| 1 | 1A |
| 2 | 1B |
| 3 | 1Y |
| 4 | 2Y |
| 5 | 2A |
| 6 | 2B |
| 7 | V _{SS} |
| 8 | 3A |
| 9 | 3B |
| 10 | 3Y |
| 11 | 4Y |
| 12 | 4A |
| 13 | 4B |
| 14 | V _{DD} |
| CONNECT CHIP BACK TO V _{DD} OR FLOAT | |

Logic Diagram



Truth Table

| INPUTS | | OUTPUT |
|--------|---|--------|
| A | B | Y |
| L | L | L |
| L | H | H |
| H | L | H |
| H | H | H |

H = High level (steady state)
L = Low level (steady state)





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Absolute Maximum Ratings¹

| PARAMETER | SYMBOL | VALUE | UNIT |
|--|-------------------|----------------------|------|
| DC Supply Voltage (Referenced to V_{SS}) | V_{DD} | -0.5 to +20 | V |
| DC Input or Output Voltage (Referenced to V_{SS}) | V_{IN}, V_{OUT} | -0.5 to $V_{DD}+0.5$ | V |
| Storage Temperature Range | T_{STG} | -65 to 150 | °C |
| Input Current or Output Current (per Pad) | I_{IN}, I_{OUT} | ±10 | mA |
| Power Dissipation in Still Air | P_D | 500 | mW |

1. Operation above the absolute maximum rating may cause device failure. Operation at the absolute maximum ratings, for extended periods, may reduce device reliability. 2. Measured in plastic DIP package, results in die form are dependent on die attach and assembly method.

Recommended Operating Conditions³ (Voltages referenced to V_{SS})

| PARAMETER | SYMBOL | MIN | MAX | UNITS |
|----------------------------------|-------------------|-----|----------|-------|
| Supply Voltage | V_{DD} | 3.0 | 18 | V |
| DC Input Voltage, Output Voltage | V_{IN}, V_{OUT} | 0 | V_{DD} | V |
| Operating Temperature Range | T_J | -55 | +125 | °C |

3. This device contains protection circuitry against damage due to high static voltages or electric fields. However, any voltage higher than maximum rated voltages to this high-impedance circuit should be avoided. For proper operation, V_{IN} & V_{OUT} should be constrained to the range $V_{SS} \leq (V_{IN} \text{ or } V_{OUT}) \leq V_{DD}$. Unused inputs must always be tied to an appropriate logic voltage level (e.g., either V_{SS} or V_{DD}). Unused outputs must be left open.

DC Electrical Characteristics (Voltages referenced to V_{SS})

| PARAMETER | SYMBOL | V_{DD} | CONDITIONS | LIMITS | | | UNITS |
|-----------------------------------|----------|----------|---|--------|-------|-------------------------|-------|
| | | | | 25°C | 85°C | FULL RANGE ⁴ | |
| Minimum High-Level Input Voltage | V_{IH} | 5V | $V_{OUT} = 0.5V$ | 3.5 | 3.5 | 3.5 | V |
| | | 10V | $V_{OUT} = 1.0V$ | 7 | 7 | 7 | |
| | | 15V | $V_{OUT} = 1.5V$ | 11 | 11 | 11 | |
| Maximum Low-Level Input Voltage | V_{IL} | 5V | $V_{OUT} = 0.5V$ or $V_{DD} - 0.5V$ | 1.5 | 1.5 | 1.5 | V |
| | | 10V | $V_{OUT} = 0.5V$ or $V_{DD} - 0.5V$ | 3 | 3 | 3 | |
| | | 15V | $V_{OUT} = 0.5V$ or $V_{DD} - 0.5V$ | 4 | 4 | 4 | |
| Minimum High-Level Output Voltage | V_{OH} | 5V | $V_{IN} = 0$ or V_{DD} | 4.95 | 4.95 | 4.95 | V |
| | | 10V | | 9.95 | 9.95 | 9.95 | |
| | | 15V | | 14.95 | 14.95 | 14.95 | |
| Maximum Low-Level Output Voltage | V_{OL} | 5V | $V_{IN} = V_{DD}$ or 0 | 0.05 | 0.05 | 0.05 | V |
| | | 10V | | 0.05 | 0.05 | 0.05 | |
| | | 15V | | 0.05 | 0.05 | 0.05 | |
| Maximum Input Leakage Current | I_{IN} | 18V | $V_{IN} = V_{DD}$ or V_{SS} | ±0.1 | ±0.1 | ±1.0 | µA |
| Maximum Quiescent Supply Current | I_{DD} | 5V | $V_{IN} = V_{DD}$ or V_{SS} $I_{OUT} = 0\mu A$ | 0.25 | 7.5 | 7.5 | µA |
| | | 10V | | 0.5 | 15 | 15 | |
| | | 15V | | 1.0 | 30 | 30 | |
| | | 20V | | 5.0 | 150 | 150 | |





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DC Electrical Characteristics Continued (Voltages referenced to V_{SS})

| PARAMETER | SYMBOL | V_{DD} | CONDITIONS | LIMITS | | | UNITS |
|--------------------------------------|----------|----------|---|--------|-------|-------------------------|-------|
| | | | | 25°C | 85°C | FULL RANGE ⁴ | |
| Minimum Output Low (Sink) Current | I_{OL} | 5V | $V_{IN} = V_{DD}$ or V_{SS} $V_{OL} = 0.4V$ | 0.64 | 0.51 | 0.36 | mA |
| | | 10V | $V_{IN} = V_{DD}$ or V_{SS} $V_{OL} = 0.5V$ | 1.6 | 1.3 | 0.9 | |
| | | 15V | $V_{IN} = V_{DD}$ or V_{SS} $V_{OL} = 1.5V$ | 4.2 | 3.4 | 2.4 | |
| Minimum Output High (Source) Current | I_{OH} | 5V | $V_{IN} = V_{DD}$ or V_{SS} $V_{OH} = 2.5V$ | -3.0 | -2.4 | -1.7 | mA |
| | | 5V | $V_{IN} = V_{DD}$ or V_{SS} $V_{OH} = 4.6V$ | -0.64 | -0.51 | -0.36 | |
| | | 10V | $V_{IN} = V_{DD}$ or V_{SS} $V_{OH} = 9.5V$ | -1.6 | -1.3 | -0.9 | |
| | | 15V | $V_{IN} = V_{DD}$ or V_{SS} $V_{OH} = 13.5V$ | -4.2 | -3.4 | -2.4 | |

5. $-55^{\circ}C \leq T_J \leq +125^{\circ}C$

AC Electrical Characteristics⁶

| PARAMETER | SYMBOL | V_{DD} | CONDITIONS | TYPICAL | LIMITS | | UNITS |
|--|--------------------|----------|---|---------|--------|-------------------------|-------|
| | | | | 25°C | 85°C | FULL RANGE ⁴ | |
| Propagation Delay, Input A or B to Output Y (Figure 1) | t_{PLH}, t_{PHL} | 5V | $C_L = 50pF,$ $R_L = 200k\Omega$ $t_r = t_f = 20ns$ | 125 | 250 | 500 | ns |
| | | 10V | | 60 | 120 | 240 | |
| | | 15V | | 45 | 90 | 180 | |
| Output Transition Time, Any Output (Figure 1) | t_{TLH}, t_{THL} | 5V | $C_L = 50pF,$ $R_L = 200k\Omega$ $t_r = t_f = 20ns$ | 100 | 200 | 400 | ns |
| | | 10V | | 50 | 100 | 200 | |
| | | 15V | | 40 | 80 | 160 | |
| Input Capacitance | C_{IN} | - | $C_L = 50pF,$ $R_L = 200k\Omega$ $t_r = t_f = 20ns$ | 5 | 7.5 | 7.5 | pF |

6. Not production tested in die form, characterized by chip design and tested in package.





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Switching Waveform

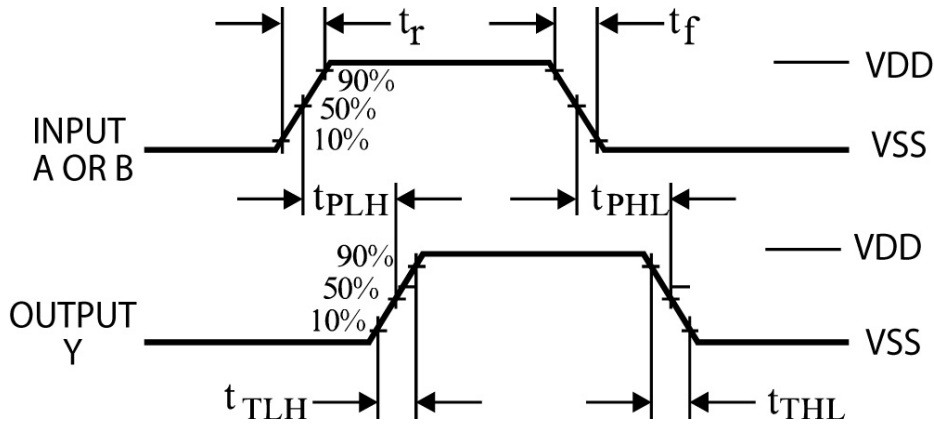


Figure 1 – Propagation Delay, Transition Timing

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